

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN THE MATTER OF THE PCT NATIONAL PHASE PATENT APPLICATION

OF: Kazuhiro FUJIKAWA et al.

USSN: to be assigned - new

FILED: March 18, 2005

FOR: Method of Fabricating Semiconductor
Device

| USPS EXPRESS MAIL
| EV 511 024 616 US
| MARCH 18 2005

INTERNATIONAL SERIAL NO.: PCT/JP2004/005649
INTERNATIONAL FILING DATE: 20 April 2004 (20.04.2004)

MS PCT
COMMISSIONER FOR PATENTS
P.O. BOX 1450
ALEXANDRIA, VA 22313-1450

March 18, 2005

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

- 1) Pursuant to 37 C.F.R. 1.56, 1.97 and 1.98 applicants are enclosing a Form PTO-1449, copies of references AD, AF, a partial English translation of reference AF, English Abstracts of references AB to AE, and a copy of the English version of the International Search Report issued in the corresponding PCT International Application PCT/JP2004/005649 on August 10, 2004. Copies of references AA to AC and AE are not (and need not be) enclosed, because they have been transmitted to the USPTO by the International Searching Authority in the International processing of this PCT Application.
- 2) This Information Disclosure Statement is being filed simultaneously with the above identified PCT Patent Application.

- 3) Reference AA is in English. A partial English translation for reference AF, and English Abstracts for references AB to AE are enclosed. References AD and AF have been discussed at page 3 of the present specification. Reference AE corresponds to AA from which the relevance can be determined in English. Therefore no further discussion of the references is necessary.
- 4) Moreover, the enclosed Search Report indicates the degree of relevance of references AC and AE by category (X = relevant for anticipation or obviousness when considered alone; and Y = relevant for obviousness when combined with another document) and discusses reference AB. Thereby, a concise explanation of the relevance has been provided (see M.P.E.P. §609).
- 5) The Examiner is requested to consider all references of record, return an initialed copy of the enclosed Form PTO-1449 and ensure that all references of record are printed on any patent issuing from this application.

Respectfully submitted,

Kazuhiro FUJIKAWA et al.
Applicant

By 

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WFF:hc/4858/PCT
Encls.:
postcard, Form PTO-1449,
English Version of
Int. Search report,
4 English Abstracts,
1 Partial English Translation,
2 references

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Sheet <u>1</u> of <u>1</u> FIRST IDS LIST OF REFERENCES CITED BY APPLICANT (FORM PTO-1449) DATED: <u>March 18, 2005</u>				Atty. Docket No. 4858/PCT		Serial No. 10/528440 to be assigned	
				Applicant: Kazuhiro FUJIKAWA et al.			
				U.S. Filing Date: March 18, 2005		Art Unit:	
U. S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	Cl.	Sub- Cl.	Fil. Date
	AA	2001/0046757	11/2001	Takahashi et al.	-	-	-
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NO.	DATE	COUNTRY	Cl.	Sub- Cl.	Trans. <div style="display: flex; justify-content: space-between; font-size: 0.8em;"> Yes No </div>
	AB	61-069174	04/1986	Japan	-	-	Abst.
	AC	04-002120	01/1992	Japan	-	-	Abst.
	AD	10-256173	09/1998	Japan	-	-	Abst.
	AE	2001-332508	11/2001	Japan	-	-	=AA +Abst.
OTHER DOCUMENTS							
	AF	Power Device, Power IC Handbook, edited by the Institute of Electrical Engineers of Japan, High Performance and High Function Power Device and Power IC Investigation and Research Committee, Corona Publishing Co., Ltd., July 1996, pp. 38-41 (with partial English translation)					
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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